



Title of Change:	SOT-553 package qualification of Assembly & Test in ON Semiconductor Leshan, China
Proposed first ship date:	17 May 2016
Contact information:	Contact your local ON Semiconductor Sales Office or <shero.gao@onsemi.com>
Samples:	Contact your local ON Semiconductor Sales Office or <shero.gao@onsemi.com>.
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <quality@onsemi.com>.
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.
Change Part Identification:	Affected products from ON semiconductor with date code 1619 representing WW19, 2016 and greater may be sourced from either the Seremban factory or the Leshan factory.
Change category:	<input type="checkbox"/> Wafer Fab Change <input checked="" type="checkbox"/> Assembly Change <input checked="" type="checkbox"/> Test Change <input type="checkbox"/> Other _____
Change Sub-Category(s):	<input checked="" type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Material Change <input type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Product specific change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Other: _____
Sites Affected:	<input type="checkbox"/> All site(s) <input type="checkbox"/> not applicable <input checked="" type="checkbox"/> ON Semiconductor site(s) : On Semiconductor Leshan Facility <input type="checkbox"/> External Foundry/Subcon site(s)
Description and Purpose:	<p>ON Semiconductor is notifying customers of the qualification and transfer of the assembly and test of SOT553 and SOT563 packages from ON Semiconductor Seremban facility to ON Semiconductor Leshan facility.</p> <p>The ON Semiconductor Leshan facility is certified with ISO/TS 16949:2009.</p> <p>The bill of materials used in the SOT553 packages will remain the same between both ON Semiconductor’s Seremban and Leshan’s facilities.</p> <p>Reliability qualification and full electrical characterization over temperature has been performed to ensure device functionality and electrical specifications are met.</p>



Reliability Data Summary:

PACKAGE : SOT563

QV DEVICE NAME:

NST3906DXV6T1G Cu wire

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150C,80% Rated Voltage	1008 hrs	0/156
HAST+PC	JESD22-A110	Ta=130 C RH=85%, ~18.8 psig, bias	96 hrs	0/156
RSH	JESD22- B106	Ta=260C, 10 sec, elec test		0/60
SD	JSTD002	Ta=245C, 10 sec		0/30
DPA		per AEC Q101 post HAST 96 hrs		0/6

QV DEVICE NAME:

NST3906DXV6T1G Cu wire

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150C,80% Rated Voltage	1008 hrs	0/78
HAST+PC	JESD22-A110	Ta=130 C RH=85%, ~18.8 psig, bias	96 hrs	0/78
RSH	JESD22- B106	Ta=260C, 10 sec, elec test		0/30
DPA		per AEC Q101 post HAST 96 hrs		0/4

QV DEVICE NAME:

NSV12100XV6T1G Cu wire

Test	Specification	Condition	Interval	Results
HAST+PC	JESD22-A110	Ta=130 C RH=85%, ~18.8 psig, bias	96 hrs	0/93
HTRB	JESD22-A108	Ta=150C,80% Rated Voltage	1008 hrs	0/78
RSH	JESD22- B106	Ta=260C, 10 sec, elec test		0/30
DPA		per AEC Q101 post HAST 96 hrs		0/4

QV DEVICE NAME:

NTZD3155CT1H Cu wire

Test	Specification	Condition	Interval	Results
Autoclave+PC	J-STD-020 JESD-A113	Ta=121C, RH=100%, ~15psig	96 hrs	0/84
HTRB	JESD22-A108	Ta=150C,80% Rated Voltage	1008 hrs	0/84
HTGB	JESD22-A108	Ta=150C,80% Rated Voltage	1008 hrs	0/84
HAST+PC	JESD22-A110	Ta=130 C RH=85%, ~18.8 psig, bias	96 hrs	0/89
HTSL	JESD22-A103	Ta=150C	1512 hrs	0/89
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=25C, delta TJ = 100C Ton=Toff = 2min	15000 cyc	0/84
TC	JESD22-A104	Ta= -65/150C	2000 cyc	0/84
RSH	JESD22- B106	Ta=260C, 10 sec, elec test		0/30
SD	JSTD002	Ta=245C, 10 sec		0/15
DPA		per AEC Q101 post TC 1k cyc		0/2
DPA		per AEC Q101 post HAST 96hrs		0/2



QV DEVICE NAME:

NUF2230XV6T1G Cu wire

Test	Specification	Condition	Interval	Results
Autoclave+PC	J-STD-020 JESD-A113	Ta=121C, RH=100%, ~15psig	96 hrs	0/84
HTRB	JESD22-A108	Ta=150C,80% Rated Voltage	1008 hrs	0/84
HTSL	JESD22-A103	Ta=150C	1512 hrs	0/89
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=25C, delta TJ = 100C Ton=Toff = 2min	15000 cyc	0/84
TC	JESD22-A104	Ta= -55/150C	2000 cyc	0/84
RSH	JESD22- B106	Ta=260C, 10 sec, elec test		0/30
SD	JSTD002	Ta=245C, 10 sec		0/15
DPA		per AEC Q101 post TC 1k cyc		0/2
DPA		per AEC Q101 post HAST 96hrs		0/2

QV DEVICE NAME:

NUP5120X6T1G Cu wire

Test	Specification	Condition	Interval	Results
Autoclave+PC	J-STD-020 JESD-A113	Ta=121C, RH=100%, ~15psig	96 hrs	0/84
HAST+PC	JESD22-A110	Ta=130 C RH=85%, ~18.8 psig, bias	96 hrs	0/89
HTRB	JESD22-A108	Ta=150C,80% Rated Voltage	1008 hrs	0/84
HTSL	JESD22-A103	Ta=150C	1512 hrs	0/89
TC	JESD22-A104	Ta= -65/150C	2000 cyc	0/84
RSH	JESD22- B106	Ta=260C, 10 sec, elec test		0/30
SD	JSTD002	Ta=245C, 10 sec		0/15
DPA		per AEC Q101 post TC 1k cyc		0/2
DPA		per AEC Q101 post HAST 96hrs		0/2

QV DEVICE NAME:

NTZS3151PT1G Cu wire

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150C,80% Rated Voltage	1008 hrs	0/84
HTGB	JESD22-A108	Ta=150C,80% Rated Voltage	1008 hrs	0/84
Autoclave+PC	J-STD-020 JESD-A113	Ta=121C, RH=100%, ~15psig	96 hrs	0/84
HAST+PC	JESD22-A110	Ta=130 C RH=85%, ~18.8 psig, bias	96 hrs	0/89
HTSL	JESD22-A103	Ta=150C	1512 hrs	0/89
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=25C, delta TJ = 100C Ton=Toff = 2min	15000 cyc	0/84
TC	JESD22-A104	Ta= -65/150C	2000 cyc	0/84
RSH	JESD22- B106	Ta=260C, 10 sec, elec test		0/30
SD	JSTD002	Ta=245C, 10 sec		0/15
DPA		per AEC Q101 post TC 1k cyc		0/2
DPA		per AEC Q101 post HAST 96hrs		0/2



PACKAGE : SOT553

QV DEVICE NAME:

NL17SZ126XV5T2G

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Tj=150C, Vcc=5.5V	1008 hrs	0/84
HTSL	JESD22-A103	Ta=150C	1008 hrs	0/84
TC	JESD22-A104	Ta= -65/150C	1000 cyc	0/84
HAST+PC	JESD22-A110	Ta130C RH=85%, ~18.8 psig, bias	96 hrs	0/84
uHAST+PC	JESD22-A118	Ta130C RH=85%, ~18.8 psig, unbias	96 hrs	0/84
RSH	JESD22- B106	Ta=260C, 10 sec, elec test		0/30
SD	JSTD002	Ta = 245C, 10 sec		0/15
DPA		per AEC Q101 post TC 500 cyc		0/2
DPA		per AEC Q101 post HAST 96hrs		0/5

Electrical Characteristic Summary:

Electrical characteristics are not impacted.

List of Affected Standard Parts:

Part Number	Qualification Vehicle
NL17SZ14XV5T2G	NL17SZ126XV5T2G
NL17SZ17XV5T2G	NL17SZ126XV5T2G
NL17SZU04XV5T2G	NL17SZ126XV5T2G